Extraction of Device Noise Sources from Measured Data Using Circuit Simulator Software (Short Papers)

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A procedure is presented for extracting the properties of device noise sources from experimental data. The extraction procedure can be implemented using commercially available circuit simulators. An example concerning a low-noise pseudomorphic HEMT shows that the two noise sources extracted from experimental data are largely uncorrelated provided that parasitic elements are de-embedded from the measurement and that the sources are extracted in H-parameter format.

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